

IC TESTER USING 89s52 MICROCONTROLLER

¹,Miss.M.A.Tarkunde, ²,Prof.Mrs.A.A.Shinde

^{1,2,}Bharati vidyapeeth Deemed University College of Engineering

Pune,India

Abstract

An IC constitues area of microelectronics in which many electronic components are combined in to high density modules.IC's, the main component of each and every electronic circuit can be used for wide variety of purposes and functions. IC consists of active and passive components such as resistors, capacitors, transistors on single chip which reduces size of system, power consumption and cost of overall system. But sometime due to faulty ICs the circuit doesn't work. It is lot work to debug the circuit and confirm whether the circuiting is creating problem or the IC is faulty. So the proposed project is designed to confirm whether the IC under consideration is properly working or not. The proposed project can be used to check the IC's of 74 series at gate level.

I. Introduction

The basic function of IC tester is to check digital IC for correct logical functioning as described in the truth table i.e. it used to test the variety of IC's which consists of gates, sequential circuits, combinational circuits. The input signals are applied to the input pins of the IC and output is measured at the corresponding output pin. In the various systems various IC's and components are connected to each other. During the system failure it is not possible to check the whole circuit as it requires much time ,and high cost. Therefore by checking only IC's and components on the chip the failure rate can be reduced by using the designed project. Unlike the Ic testers available in market ,this IC tester is affordable and user friendly. The 89s52 microcontroller is used in this project with keyboard and LCD display unit. It checks the gates in given IC which is placed in ZIF socket and display the result. Testing of IC is based on the inputs that provided to the gates in IC through the programming.

Ii.Lite rature Survey

The proposed project is used to check the digital IC's. Digital IC's are consists of two types.

1.Microcontroller based

2.PC based

The proposed project checks only microcontroller based IC's. Various types of microcontrollers are available in the market to check the correct functionality of component and IC's such as

i.8051 ii.89c2051 iii.89s52

DISADVANTAGES OF 8051

t gulps power and so it heats up.
t is not CMOS compatible, only TTL compatible.

Disadvantage of 89c2051

1.it is 20 pin IC.
2.AS we are testing 16/14 pin IC this IC is not sufficient.
3.it is not possible to interface keyboard and display.

ADVANTAGES OF 89s52 MICROCONTROLLER

- 1.8K Bytes of In-System Programmable (ISP) Flash Memory
- Endurance: 1000 Write/Erase Cycles

_	
Issn 2250-3005(online)

November | 2012

Page 24



- 4.0V to 5.5V Operating Range
- Fully Static Operation: 0 Hz to 33 MHz
- Three-level Program Memory Lock
- 256 x 8-bit Internal RAM
- 32 Programmable I/O Lines
- Three 16-bit Timer/Counters
- Eight Interrupt Sources
- Full Duplex UART Serial Channel
- Low-power Idle and Power-down Modes
- Interrupt Recovery from Power-down Mode
- Watchdog Timer
- Dual Data Pointer
- Power-off Flag

Iii.Block Diagram



Iv.Working

1.Power supply design

The basic step in the designing of any system is to design the power supply required for that system.



BRIDGE RECTIFIER

We have used Regulator

IC 7805 that gives output voltage of 5V. The minimum input voltage required

for the 7805 is near about 7 v. Therefore we have used the transformer with the voltage rating 230v-10v and current rating 500 mA. The output of the transformer is 12 V AC. This Ac voltage is converted into 12 V DC by Bridge rectifier circuit.

2.LCD display

Issn 2250-3005(online)	November 2012	Page 25
------------------------	-----------------	---------



We have used 16*2 LCD display which has 8 data lines and 3 control lines. The connections of LCD are given blow

2			
·	VCC	91	VCC +5V (FOR LCD)
		2	CONTRAST CONNECTED TO GND GOR CHINA MADE LCD
· •	LCDRS	3	LCD REGISTER SELECT RS
· · ·	LCDRW	4	LCD READ WRITE R/W
÷	LCDEN	5	LCD ENABLE EN
	LD0	6	LCD DATA LINE DO
	LD1	7	LCD DATA LINE D1
	LD2	8	LCD DATA LINE D2
	LD3	9	LCD DATA LINE D3
	LD4	10	LCD DATA LINE D4
	LD5	y 11	LCD DATA LINE D5
	LD6	12	LCD DATA LINE D6
5V	R15 LD7	13	LCD DATA LINE D7
T		14	VCC + 5V FOR BACK LIGHT
		15	GND FOR BACK LIGHT
	10E	16	
			ONNECTOR(16x2)

3.Keypad

It has 4 keys to select proper IC which we want to check.



Working of gate level testing of IC

The test sequence for IC testing is as given below,

- 1. The ISP programmer is used to download the program in the microcontroller.
- 2. the project is made user friendly by interfacing keypad and LCD.
- 3. The IC to be tested is inserted in the ZIF socket. The user enters the IC number through keypad which is simultaneously

displayed on the LCD.

- 4. The IC number is communicated to microcontroller which basically test the ICs for few sets of input which is given through the MCU and corresponding output. The result is again displays on the LCD.
- 5. If the IC tested is ok "IC TESTED OK is displayed on the LCD. Otherwise "IC TESTED FAILED" is displayed.

V. Flow Chart



Vi.Conclusion

This paper proposes an inexpensive and compact model of digital integrated circuit tester using 89s52.Diffrent digital IC's can be tested by just writing the specific program without any change in hardware. Depending upon predetermined data the signals from microcontroller are conditioned and corresponding output pins are checked for

		•
Issn 2250-3005(online)	November 2012	Page 26



correctness The system that has been implemented has shown considerable output that matched our requirment.this was achived by small and user friendly 89s52.

Vii.References

- 1. Abhishek Jain, Anshul Goyal ,Siddharth Garg,"DigitalIC tester"*Electronics club*, *IIT* Kanpur
- 2. Fang pang, Canada" A reconfigurable digital IC tester implemented using ARM".
- 3. Ali F.Shammari''Design and implementation of digitalIC interface to IBM compatible computer''Scientific journalof Kerbala, university 2010
- 4. www.scribd.com"digital IC Tester ieee.
- 5. Konemann, B Zwiehoff, G Mucha J,"Built in test for complex digital IC".solid state circuit. IEEE journal ,volume 15, issue 3
- 6. K.R.Botkar"Integrated circuits",Khanna publication.
- 7. Roshan Borkar, Ashvin Nakman,"Digital Integrated Circuit Tester", Don Bosco Institute of Technology, Mumbai.
- 8. Online teaching laboratory on embedded systems,"Microcontroller based diode and BJT tester". 2009
- 9. Dhananjay v. Garde"Programming and customizing the avr microcontroller",
- 10. Online teaching laboratory on embedded systems,"Microcontroller based diode and BJT tester".2009
- 11. Dhananjay v. Garde"Programming and customizing the avr microcontroller"
- 12. www.scienceprog.com
- 13. http://extremeelectronics.co.in/avr-tutorials